

The diagram illustrates a scanning electron microscope (SEM) system. At the top, a cathode ray tube (CL) emits an electron beam (IL) through a lens (IL) and a series of lenses (1, 2, 3, 4, 5a, 5b, 6, 7, 8, 9a, 9b, 10, 11a, 11b) to a specimen (17). The specimen is mounted on a stage (15) with a piezoelectric transducer (16) and a detector (18). The system is controlled by a MASTER CONTROL SYSTEM (19) and an IMAGERY CHARACTERISTIC CONTROL SYSTEM (20). A coordinate system (X, Y, Z) is shown at the bottom left. The diagram is labeled with various components and their interconnections.

FIGURE 1

FIGURE 2

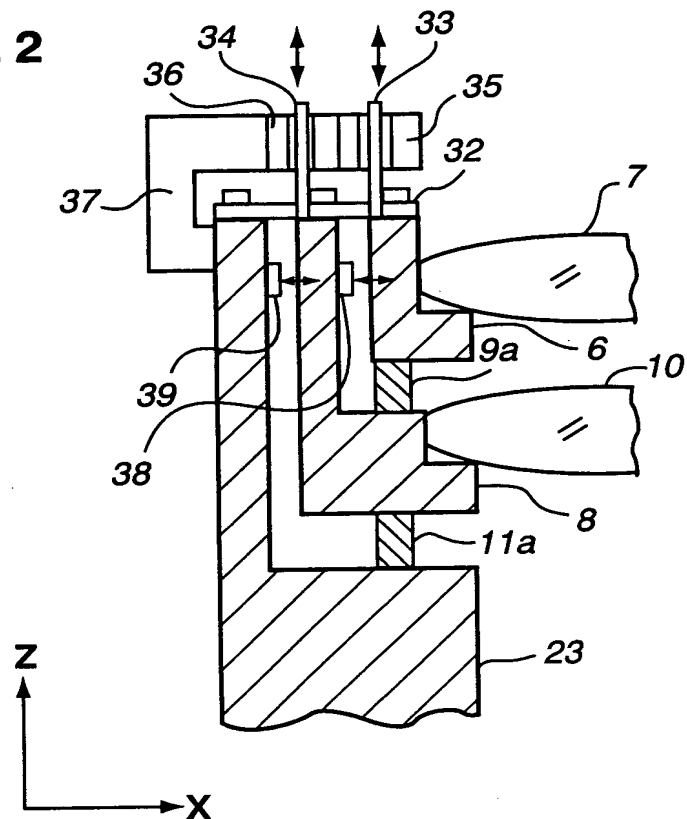


FIGURE 3

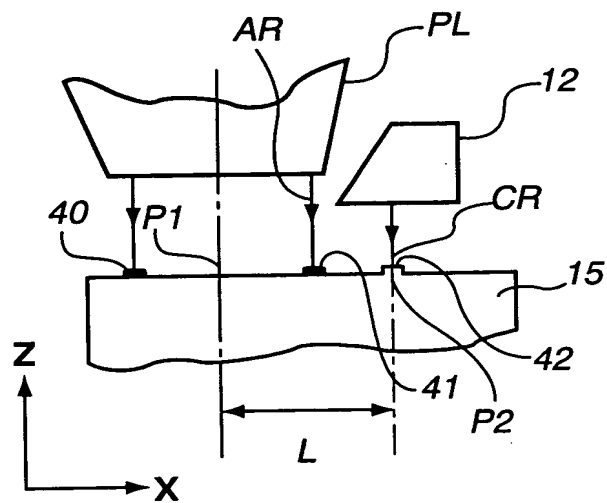


FIGURE 4(a)

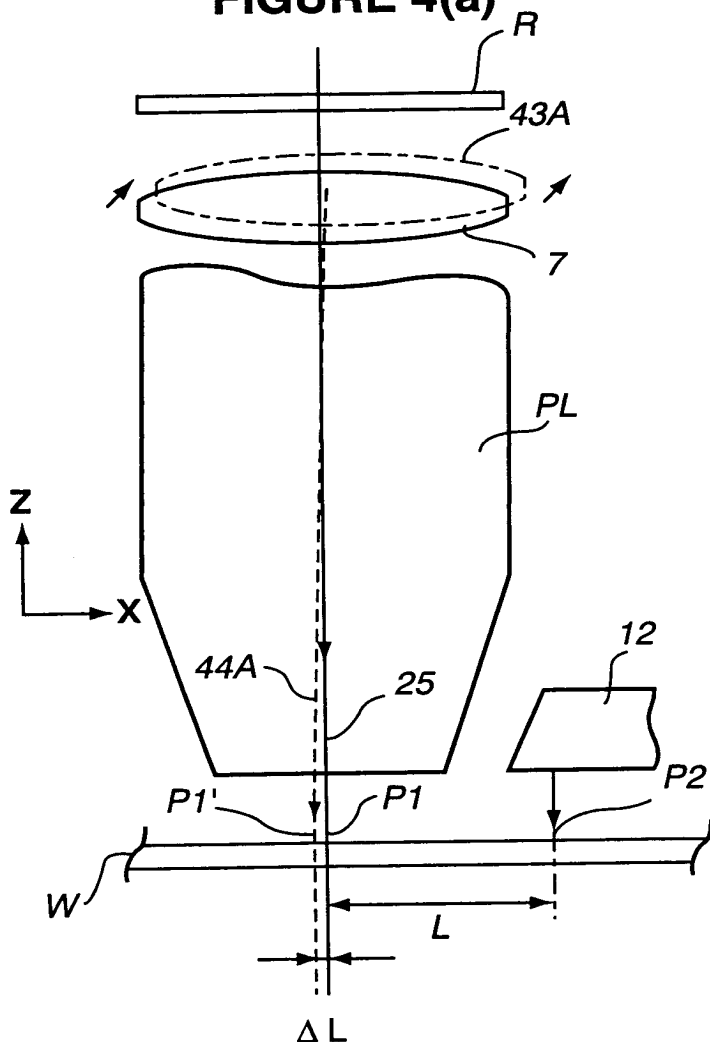


FIGURE 4(b)

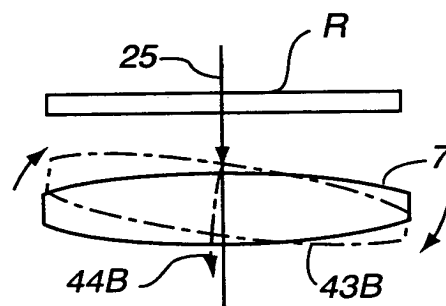


FIGURE 4(c)

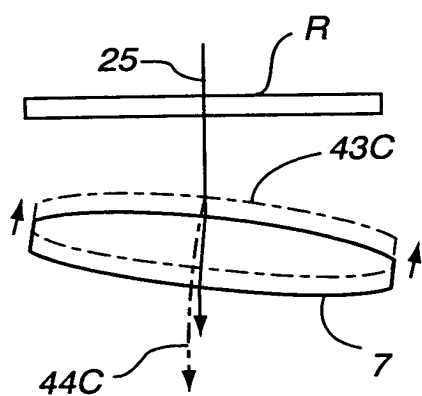


FIGURE 4(d)

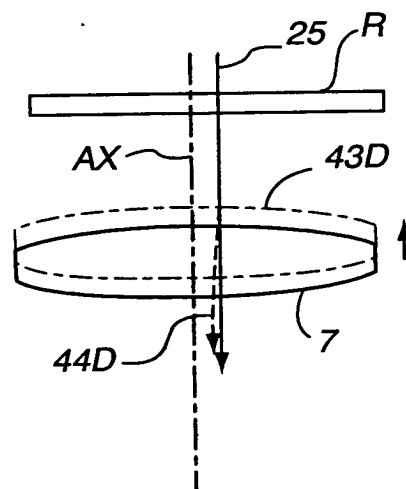


FIGURE 5

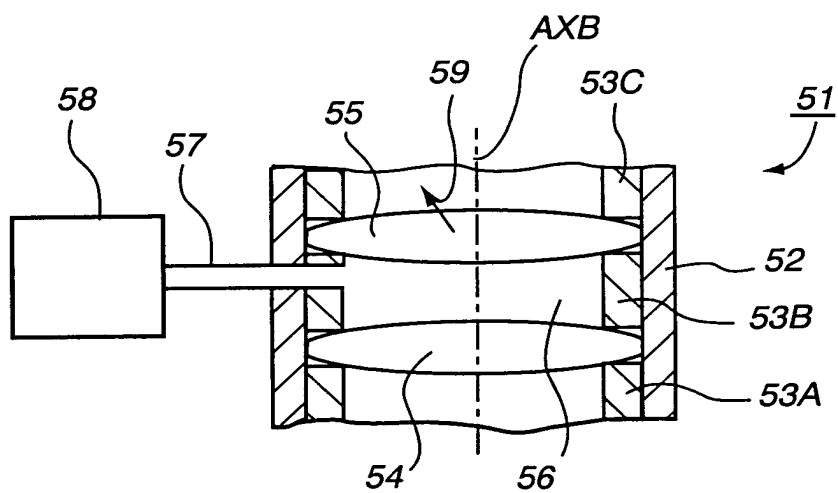




FIGURE 6

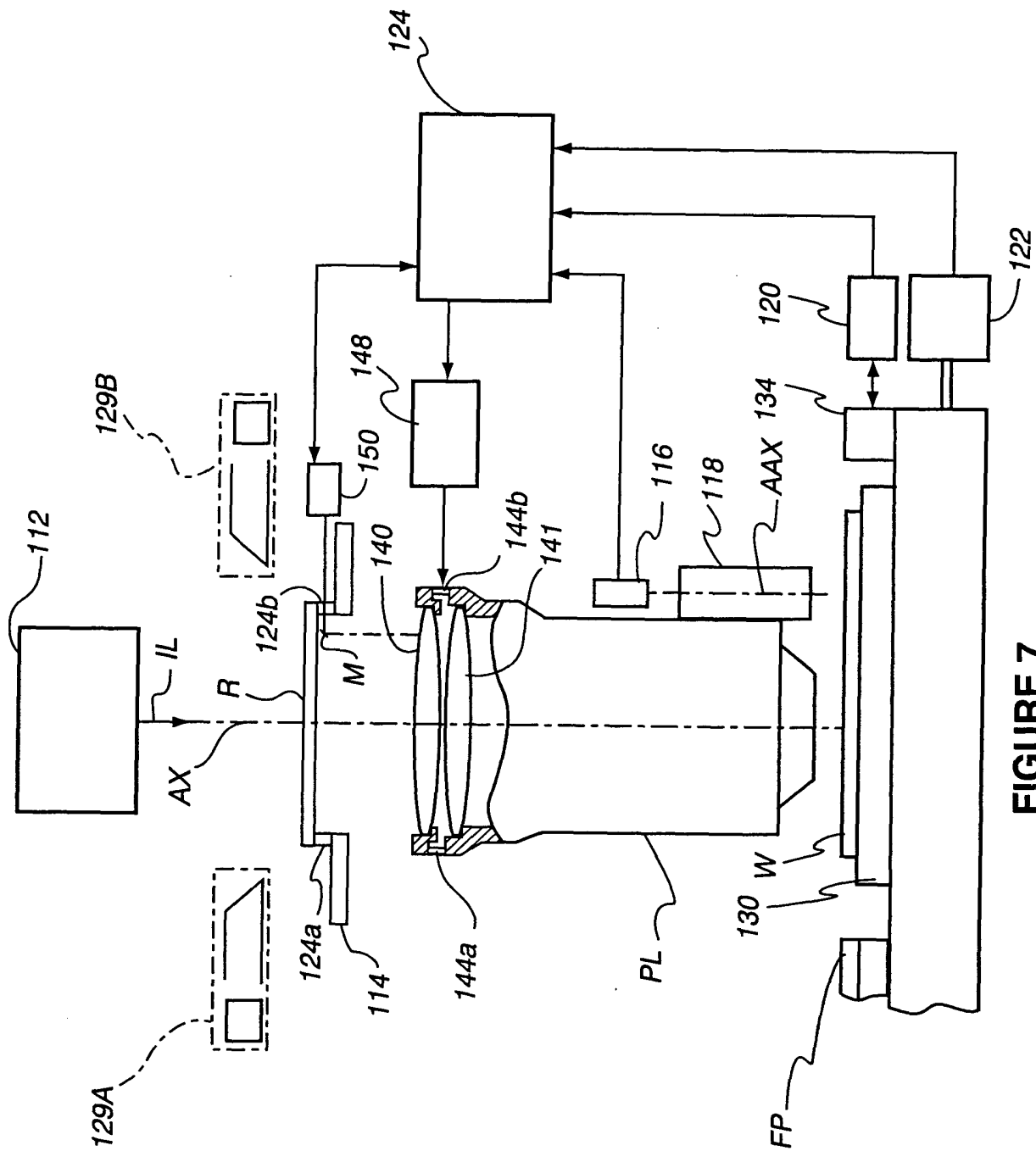


FIGURE 7

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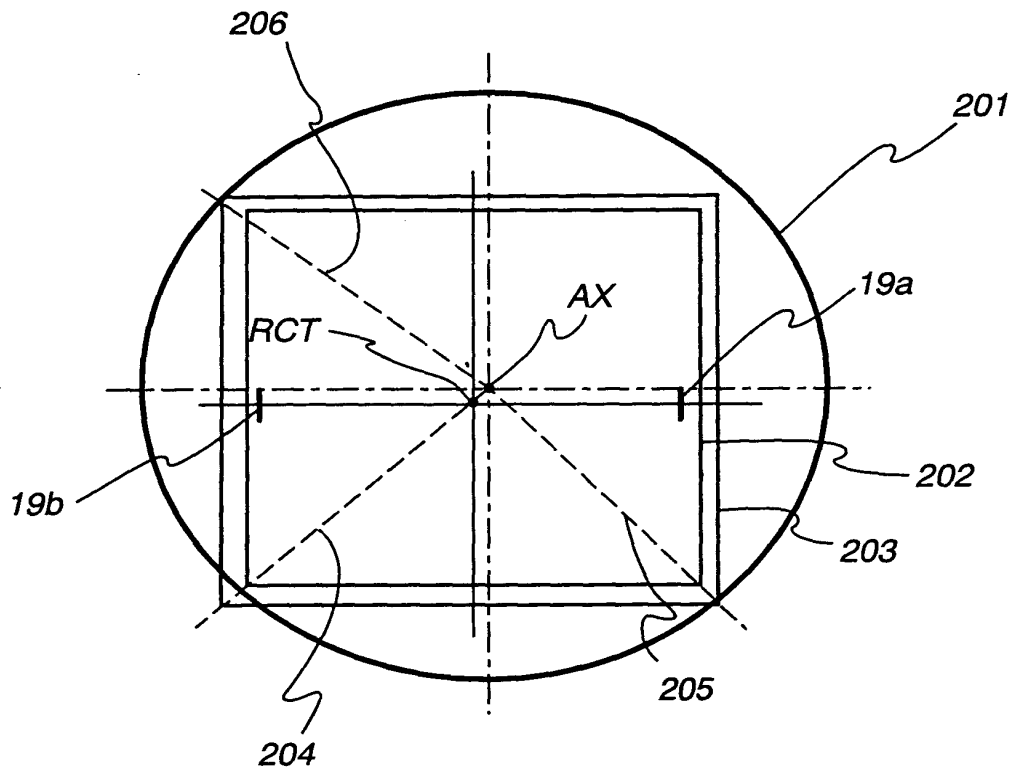


FIGURE 8